



SHEET 1 OF 1

LIST OF ART CITED BY APPLICANT
(PTO-1449)ATTY. DOCKET NO.
P-0568APPLN. SERIAL NO..
10/714,602

APPLICANT(S)

Min-Ho PARK

FILING DATE
November 18, 2003GROUP
2835**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>MS</i>	08-055534	02/27/1996	Patent Abstracts of Japan				X
<i>MS</i>	06-267369	09/22/1994	Patent Abstracts of Japan				X
<i>MS</i>	08-050831	02/20/1996	Patent Abstracts of Japan				X
<i>MS</i>	07-312137	11/28/1995	Patent Abstracts of Japan				X
<i>MS</i>	10-162689	06/19/1998	Patent Abstracts of Japan				X
<i>MS</i>	11-255928	09/21/1999	Patent Abstracts of Japan				X

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

EXAMINER

HUNG VAN DUONG

DATE CONSIDERED

5/5/06

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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SHEET 1 OF 1

LIST OF ART CITED BY APPLICANT
(PTO-1449)ATTY. DOCKET NO.
P-0401APPLN. SERIAL NO.
10/607,560

APPLICANT(S)

Doo-Hwan JO

FILING DATE
June 27, 2003GROUP
2682**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Abstract Translation	
						Yes	No
MS	EP 0 364 935	04/25/1990	EUROPE				
MS	JP 60-217752	10/31/1985	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 10-304036	11/13/1998	JAPAN (English Abstract and Japanese Full Text)			X	
MS	EP 0 232 096 A2	08/12/1987	EUROPE				
MS	EP 0 232 096 A3	08/12/1987	EUROPE (Abstract Only)				
MS	JP 11-266489	09/28/1999	JAPAN (English Abstract and Japanese Full Text)			X	

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U.S. PATENT APPLICATION PUBLICATIONS

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MS	JP 08-055534	02/27/1996	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 06-267369	09/22/1994	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 08-050831	02/20/1996	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 07-312137	11/28/1995	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 10-162689	06/19/1998	JAPAN (English Abstract and Japanese Full Text)			X	
MS	JP 11-255928	09/21/1999	JAPAN (English Abstract and Japanese Full Text)			X	

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MS Official Action dated October 31, 2005 in Japanese Patent Application No. 2004-39095.

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